



5/9/2009

RELIABILITY MONITOR REPORT
FOR

MFN 250V Bipolar CMOS DMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX4802CXZ+	MAX4990ETD+
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 1786 FITS: 63.9

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 1/1/2008 and 12/31/2008.

Process Information:

Process Description: MFN 250V Bipolar CMOS DMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0728	MAX4990ETD+	135C	192 HRS	48	0	NFVZBQ002CQ
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0728	MAX4802CXZ+	150C	1000 HRS	77	0	NEE1HA016Q1
STORAGE LIFE	0728	MAX4802CXZ+	150C	1000 HRS	77	0	NEE1HA016Q2
STORAGE LIFE	0728	MAX4802CXZ+	150C	1000 HRS	77	0	NEE1HA016Q3
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0728	MAX4802CXZ+	-65C TO 150C	1000 CYS	77	0	NEE1HA016Q1
TEMP CYCLE, 5' RAMP, 10' DWELL	0728	MAX4802CXZ+	-65C TO 150C	1000 CYS	77	0	NEE1HA016Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	0728	MAX4802CXZ+	-65C TO 150C	1000 CYS	77	0	NEE1HA016Q3
TEMP CYCLE, 5' RAMP, 10' DWELL	0751	MAX4990ETD+	-65C TO 150C	1000 CYS	500	0	NFVZBA008AA
TEMP CYCLE, 5' RAMP, 10' DWELL	0802	MAX4990ETD+	-65C TO 150C	1000 CYS	500	0	NFVZBA004DX
Total:						0	

FAILURE RATE: MTTF (YRS): 1786 FITS: 63.9